				Application/0	Control No.	Applicant(s)/	Patent Under	
No. 45 and 15 an				10/667,668			Applicant(s)/Patent Under Reexamination FUKUDA ET AL.	
		Notice of Reference	Examiner	Examiner				
				Erin D. Chier	Erin D. Chiem		Page 1 of 1	
				U.S. PATENT DOCUM	ENTS			
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY		Name		Classification	
*	Α	US-6,597,497	07-2003	Wang et al.			359/344	
	В	US-						
	С	US-						
	D	US-	ļ- 					
	Ε	US-						
	F	US-	1					
	G	US-						
	Н	US-						
	ı	US-						
	J	US-						
	К	US-						
	L	US-						
	М	US-						
			•	FOREIGN PATENT DOC	UMENTS			
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Na	ime	Classification	
	N							
	0							
	Ρ							
<u> </u>	Q							
	R							
	S							
	Т							
				NON-PATENT DOCUM	IENTS		<u></u>	
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	ı							
	v							
	V							
	v W							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.